Search Notes

Application/Control No.	Applicant(s)/Patent under. Reexamination	
09/820,395	CHEN ET AL.	
Examiner	Art Unit	
Dmitry Levitan	2662	

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SEARCHED					
Class	Subclass	Date	Examiner		
370	352- 356				
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379	225	7/2			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
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